

<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/806,170	ONISHI, KAZUYOSHI
	Examiner Tran N. Nguyen	Art Unit 2834

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
<p>(29/596, 598, 837 868, 506, 734 512, 507, 736, 513) and (slot some (in slat \$ lined))</p>	<p>4/15/105</p>	<p>JW</p>

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner